

Enhancement Mode N-Channel Power MOSFET

 $TO-252/NMOS/40V/\pm20V/1.85V/50A/7.8m\Omega$

Rev0.5





40V, 7.8mΩ, 50A, Single N-Channel

1.Features

- ♦ 40V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V

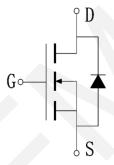
2.A	pp	lica	tio	ns
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- ♦ Power Switching Application
- Load Switching



Pin Description





Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP4060KA	WP4060K	TO-252	2,500	25,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	40	V
Gate to Source Voltage	V_{GSS}	±20	٧
Drain Current (DC)	l _D	50	А
Drain Current (Pulse), PW≤300μs	I _{DP}	200	А
Total Dissipation	P_{D}	64	W
Avalanche Energy, Single Pulsed	Eas	110	mJ
Junction Temperature	Tj	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	Rejc	1.69	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

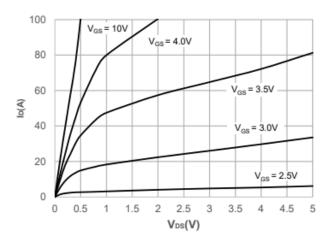
6.Electrical Characteristics at Ta=25°C (Note 3)

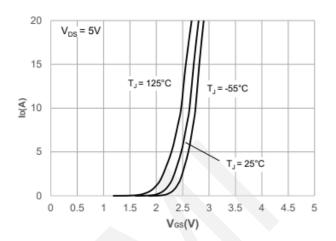
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A$, $V_{GS} = 0 V$	40	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 40V, V _{GS} = 0V	-	_	1	μΑ
Gate to Source Leakage Current	I _{GSS1}	$V_{GS} = \pm 20V, V_{SS} = 0V$	ı	-	±100	nA
Gate Threshold Voltage	$V_{\text{GS(th)}}$	V _{DS} =V _{GS} , I _{DS} =250µA	1.0	1.85	2.5	٧
Static Drain to Source On-State	Б	I _D = 30A, V _{GS} = 10V	ı	7.8	10	mΩ
Resistance	R _{DS(on)}	I _D = 20A, V _{GS} = 4.5V	-	11	16	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,		2419		pF
Output Capacitance	Coss	V _{DS} =20V,		713		pF
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz		535		pF
Turn-ON Delay Time	t _{d(on)}	V _{DS} = 20V,		12		ns
Rise Time	tr	$I_D = 30A$,		11		ns
Turn-OFF Delay Time	$t_{d(off)}$	V _{GS} = 10V,		39		ns
Fall Time	t _f	$R_G = 3\Omega$		12		ns
	Qg	V _{DS} = 20V,		54.3		nC
Total Gate Charge	Qgs	V _{GS} = 10V,		6.9		nC
	Q_{gd}	I _D = 30A		14.5		nC
Diode Forward Voltage	V_{FSD}	I _S = 30A, V _{GS} = 0	0.4	0.9	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



7. Typical electrical and thermal characteristics

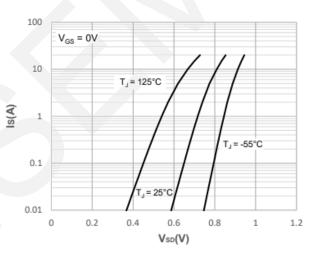




Output Characteristics

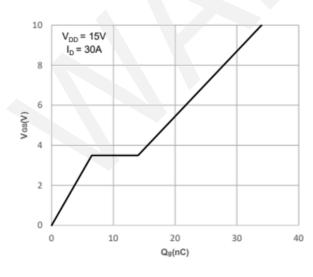
14 13 12 11 Vgs=4.5V 10 9 8 Vgs=10V 7 6 5 0 10 20 30

Typical Transfer Characteristics

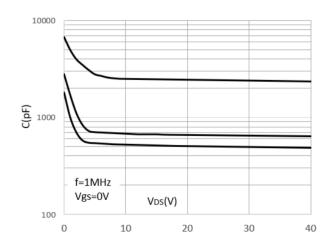


On-resistance vs. Drain Current

ID(A)



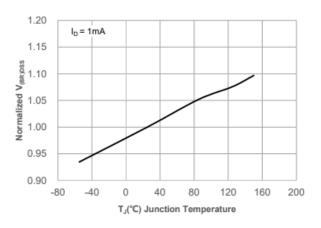
Body Diode Characteristics



Gate Charge Characteristics

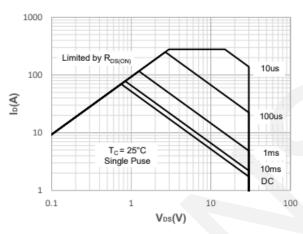
Capacitance Characteristics



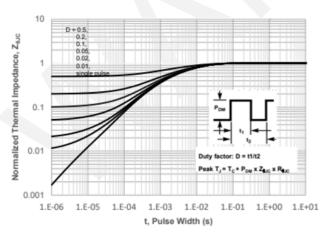


Normalized Breakdown Voltage vs.

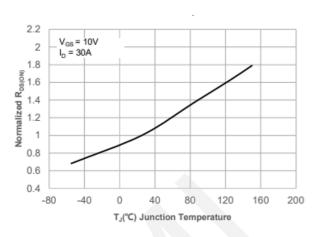
Junction Temperature



Maximum Safe Operating Area

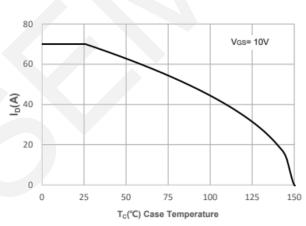


Normalized Maximum Transient
Thermal Impedance



Normalized on Resistance vs.

Junction Temperature

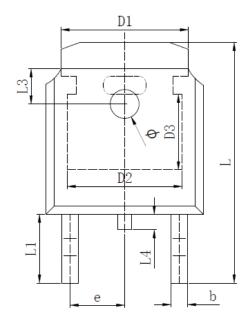


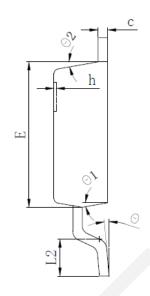
Maximum Continuous Drain Current vs.

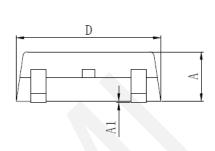
Case Temperature



8.Package Dimensions







SYMBOL	MILLIMETER				
	MIN	Тур.	MAX		
A	2. 200	2. 300	2. 400		
A1	0.000		0. 127		
b	0. 640	0.690	0. 740		
c(电镀后)	0. 460	0.520	0. 580		
D	6. 500	6. 600	6. 700		
D1	5.334 REF				
D2	4.826 REF				
D3	3.166 REF				
E	6. 000	6. 100	6. 200		
е	2.286 TYP				
h	0.000	0. 100	0. 200		
L	9. 900	10. 100	10. 300		
L1	2.888 REF				
L2	1. 400	1. 550	1. 700		
L3	1.600 REF				
L4	0.600	0.800	1. 000		
ф	1. 100	1. 200	1. 300		
θ	0°		8°		
θ 1	9° TYP				
θ2	9° TYP				



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